

Institute of Electrical and Electronic Engineers

University of Connecticut Student Branch General Meeting

**Monday
November 9th
ITEB 336
6:00PM**

**Free
Refreshments!**

Open Meeting!

All current members, and any students interested in the subject topic are welcome.

Please be on time for the meeting.

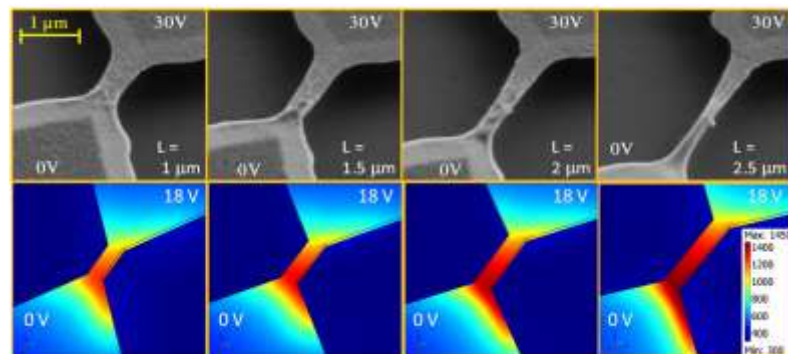
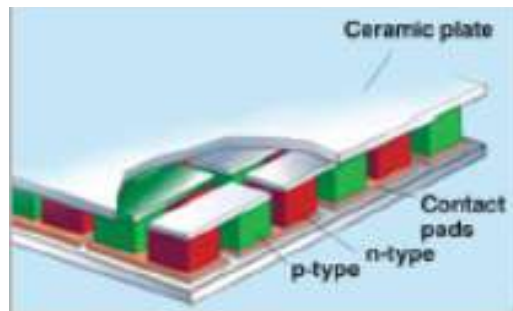
For meeting details and agenda, please visit:
iee.uconn.edu

Current Induced Crystallization & Thermoelectric Effects in Si μ -wires

Professor Ali Gokirmak

**Electrical & Computer Engineering
University of Connecticut**

Short duration large amplitude electrical stresses result in melting of Si μ -wires and growth from melt takes place after the stress. The electrical current density can reach up to ~ 100 MA/cm² during the process. These extreme current densities has lead to observation of asymmetric melting, attributed to significant electron-phonon scattering. This thermoelectric effect (phonon-drag) is a component of Thomson effect which is related to more commonly known Peltier and Seebeck effects.



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